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## Patent Search

Invention Title	EXPLORING INNOVATIVE METHODS, IOT INTEGRATION, AND ADVANCED DATA ANALYTICS FOR ENHANCING SUSTAINABLE AND EFFICIENT AGRICULTURAL YIELD
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#### Abstract:

EXPLORING INNOVATIVE METHODS, IOT INTEGRATION, AND ADVANCED DATA ANALYTICS FOR ENHANCING SUSTAINABLE AND EFFICIENT AGRICULTURAL YIELD A met development of some implementations of the invention offer techniques that can make large-area complex patterns for nanoimprint molds without or with very little the direct-writing of nanostructures by a charged beam or photon beam. A computer system's implementation of an IoT integration platform can gather data from or IoT devices, server systems designed specifically for IoT solutions, server systems owned by third parties, general-purpose user computing devices, or any combinatic This article describes systems and procedures for creating an agronomic yield map using a map of field health imaging. In one implementation, a field health image n particular agricultural field is sent to a computer system for agricultural intelligence. The server uses agricultural data records to calculate weather index values that r crop stress on plants. From the weather index values, geo-specific weather indices are created, which are then combined to create aggregated weather index data sermethod calculates a specific state agricultural yield from the covariate matrix for a specific year. It does this using linear regression. Using the total of the state crop y given year, nationally adjusted, the technique calculates the national crop yield for that year. A mutant of the strain with all of the strain's distinguishing features, or a extract of it, where the vigor and/or crop production of agricultural plants are increased under virtually no pathogen pressure. FIG.1

#### **Complete Specification**

Description: EXPLORING INNOVATIVE METHODS, IOT INTEGRATION, AND ADVANCED DATA ANALYTICS FOR ENHANCING SUSTAINABLE AND EFFICIENT AGRICULTURA Technical Field

[0001] The embodiments herein generally relate to a method for exploring innovative methods, IOT integration, and advanced data analytics for enhancing sustai and efficient agricultural yield.

Description of the Related Art

[0002] Clearly, a workable solution to the issue may completely change the industry. The current invention is concerned with solutions to this issue. The technolog recognize and profile the nearby connected devices, communicate with them, and establish logical relationships between people, objects, places, digital channels, o combination of them. The yield map for agriculture is very useful to farmers. A farmer can spot changes in the agronomic environment that affect the crop's agronc yield by using the agronomic yield map. Growers use computer-implemented crop production forecast models to decide on their cultivation plan while making suc strategic judgements. Farmers and other agricultural cultivators frequently need to analyze a range of data in order to make strategic decisions both before and thr the crop growing phase. A grower may be able to forecast important agricultural outcomes, such as crop production, energy use, cost and resource utilization, and a profitability, by analyzing these choice constraints.

[0003] With the newly developed techniques, large-area complex patterns for nanoimprint molds can be produced with little to no direct writing of nanostructure charged or photon beams. In order to determine a specific semantic label or context that is pertinent to the user, the data analysis module analyses the acquired dimetadata. One or more devices are often used to measure the agronomic yield at each position on the agronomic field in order to build an agronomic yield map. In

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